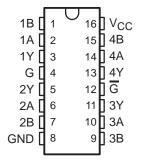
SLLS008D - JUNE 1986 - REVISED MAY 1995

- Meets or Exceeds ANSI Standard EIA/TIA-422-B and EIA/TIA-423-A and ITU Recommendations V.10 and V.11
- Designed for Multipoint Bus Transmission on Long Bus Lines in Noisy Environments
- 3-State Outputs
- Common-Mode Input Voltage Range
 7 V to 7 V
- Input Sensitivity . . . ±200 mV
- Input Hysteresis . . . 120 mV Typ
- High Input Impedance . . . 12 kΩ Min
- Operates from Single 5-V Supply
- Low Supply Current Requirement 35 mA Max
- Improved Speed and Power Version of the AM26LS32A

SN75ALS193...D, J OR N PACKAGE (TOP VIEW)



description

The SN75ALS193 is a monolithic quadruple line receiver with 3-state outputs designed using advanced low-power Schottky technology. This technology provides combined improvements in bar design, tooling production, and wafer fabrication. This, in turn, provides significantly lower power requirements and permits much higher data throughput than other designs. This device meets the specifications of ANSI Standards EIA/TIA-422-B and EIA/TIA-423-A and ITU Recommendations V.10 and V.11. It features 3-state outputs that permit direct connection to a bus-organized system with a fail-safe design that ensures the outputs will always be high if the inputs are open.

The device is optimized for balanced multipoint bus transmission at rates up to 20 megabits per second. The input features high input impedance, input hysteresis for increased noise immunity, and an input sensitivity of \pm 200 mV over a common-mode input voltage range of -7 to 7 V. It also features active-high and active-low enable functions that are common to the four channels. The SN75ALS193 is designed for optimum performance when used with the 'ALS192 quadruple differential line driver.

The SN75ALS193 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each receiver)

DIFFERENTIAL INPUTS	ENABLES		OUTPUT
A – B	G G		Υ
V _{ID} ≥ 0.2 V	H	X	H
	X	L	H
−0.2 V < V _{ID} < 0.2 V	H	X	?
	X	L	?
V _{ID} ≤ −0.2 V	H	X	L
	X	L	L
X	L	Н	Z
Open	H	X	H
	X	L	H

H = high level, L = low level, X = irrelevant, ? = indeterminate, Z = high impedance (off)



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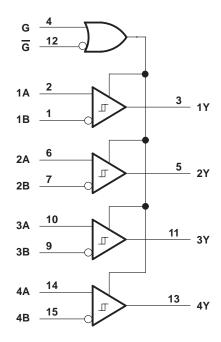


logic symbol†

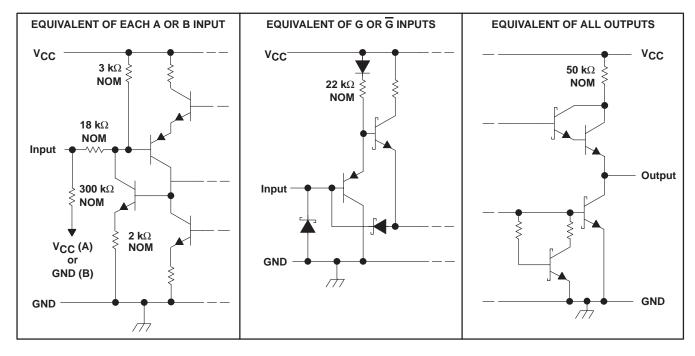
≥ 1 ΕN 12 G ⅎ 2 1A 3 1Y ∇ 1B -5 2Y 2A 7 2B 10 11 3Y **3A** 9 3B 14 4A 13 4Y 15 4B

[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



schematics of inputs and outputs



SLLS008D - JUNE 1986 - REVISED MAY 1995

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC} (see Note 1)	
Input voltage, V _I (A or B)	
Differential input voltage, V _{ID} (see Note 2)	±15 V
Enable input voltage, V _I	
Low-level output current, IOL	50 mA
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range, T _{stq}	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 60 seconds	300°C

[†] Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential input voltage, are with respect to network ground terminal.

2. Differential-input voltage is measured at the noninverting input with respect to the corresponding inverting input.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{$A$}} \leq 25^{\circ}\mbox{$C$}$ POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING
J	1025 mW	8.2 mW/°C	656 mW
N	1150 mW	9.2 mW/°C	736 mW

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.75	5	5.25	V
Common-mode input voltage, V _{IC}			±7	V
Differential input voltage, V _{ID}			±12	V
High-level input voltage, VIH	2			V
Low-level input voltage, V _{IL}			0.8	V
High-level output current, I _{OH}			-400	μΑ
Low-level output current, IOL			16	mA
Operating free-air temperature, T _A	0		70	°C



SLLS008D - JUNE 1986 - REVISED MAY 1995

electrical characteristics over recommended range of common-mode input voltage, supply voltage, and operating free-air temperature (unless otherwise noted)

PARAMETER		TEST C	TEST CONDITIONS [†]		TYP [‡]	MAX	UNIT
V _{IT+}	Positive-going input threshold voltage					200	mV
VIT-	Negative-going input threshold voltage			-200§			mV
V _{hys}	Hysteresis voltage (V _{IT+} –V _{IT} –)				120		mV
٧ıK	Enable-input clamp voltage	$V_{CC} = MIN,$	$I_{I} = -18 \text{ mA}$			-1.5	V
VOH	High-level output voltage	$V_{CC} = MIN,$ $I_{OH} = -400 \mu A,$	V _{ID} = 200 mV, See Figure 1	2.5	3.6		٧
VOL	Low-level output voltage	$V_{CC} = MIN,$	I _{OL} = 8 mA			0.45	V
		$V_{ID} = -200 \text{ mV},$ See Figure 1	I _{OL} = 16 mA			0.5	
	I Pak Sama da a sa atata a start a sama d	Van MAY	V _O = 2.4 V			20	μΑ
loz	High-impedance-state output current	VCC = MAX	V _O = 0.4 V			-20	
ΙΙ	Line input current	Other input at 0,	V _{CC} = MIN, V _I = 15 V		0.7	1.2	mA
		See Note 3	$V_{CC} = MIN,$ $V_{I} = -15 \text{ V}$		-1.0	-1.7	
1	High level enable input compart	V MAY	V _{IH} = 2.7 V			20	
lιΗ	High-level enable-input current	VCC = MAX	V _{IH} = MAX			100	μΑ
IJЦ	Low-level enable-input current	V _{CC} = MAX,	V _{IL} = 0.4 V			-100	μΑ
	Input resistance			12	18		kΩ
los	Short-circuit output current	$V_{CC} = MAX,$ $V_{O} = 0,$	V _{ID} = 3 V, See Note 4	-15	-78	-130	mA
Icc	Supply current	$V_{CC} = MAX$,	Outputs disabled		22	35	mA

[†] For conditions shown as MIN or MAX, use the appropriate values specified under recommended operating conditions.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low-to-high-level output	$V_{ID} = -2.5 \text{ V to } 2.5 \text{ V},$		15	22	
tPHL	Propagation delay time, high-to-low-level output	C _L = 15 pF, See Figure 2		15	22	
^t PZH	Output enable time to high level	C _I = 15 pF, See Figure 3		13	25	20
tPZL	Output enable time to low level	CL = 15 pr, See Figure 5		11	25	ns
tPHZ	Output disable time from high level	Cr _ E nE Son Figure 3		13	25	
tPLZ	Output disable time from low level	C _L = 5 pF, See Figure 3		15	22	



[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[§] The algebraic convention, in which the less positive limit is designated minimum, is used in this data sheet for threshold voltage levels only. NOTES: 3. Refer to ANSI Standard EIA/TIA-422-B and EIA/TIA-423-A for exact conditions.

^{4.} Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

PARAMETER MEASUREMENT INFORMATION

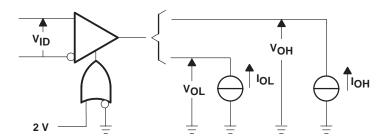
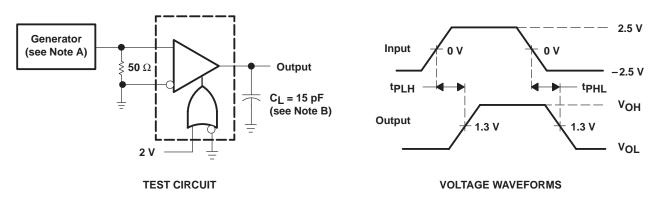


Figure 1. V_{OH}, V_{OL}

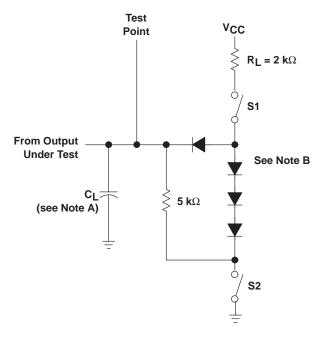


NOTES: A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, duty cycle \leq 50%, $Z_O = 50 \Omega$, $t_f \leq 6$ ns, $t_f \leq 6$ ns.

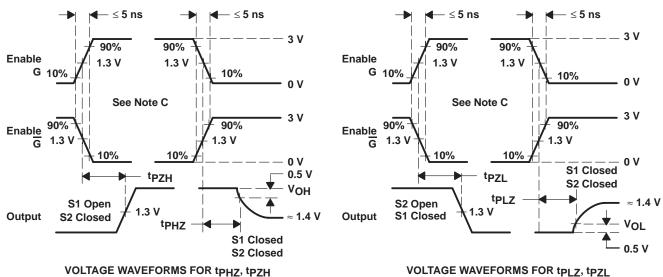
B. C_L includes probe and jig capacitance.

Figure 2. Test Circuit and Voltage Waveforms

PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT

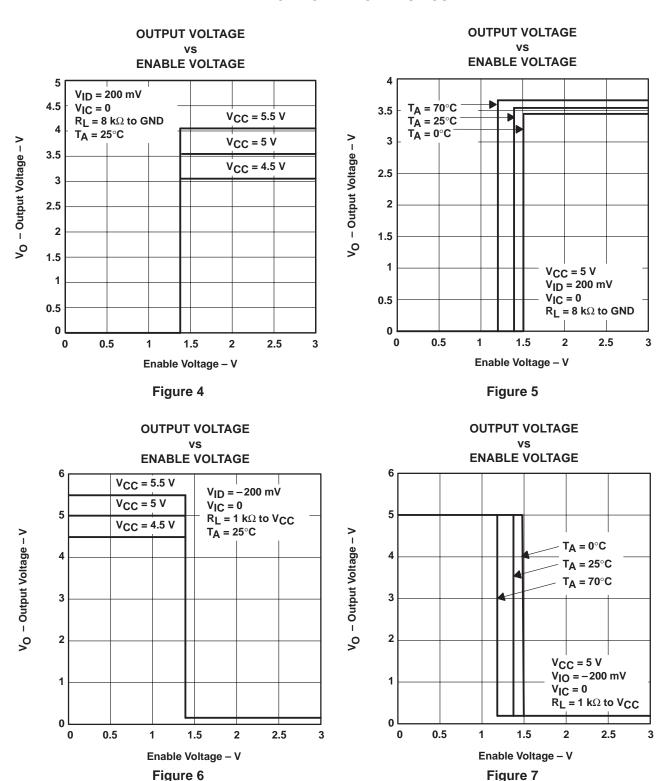


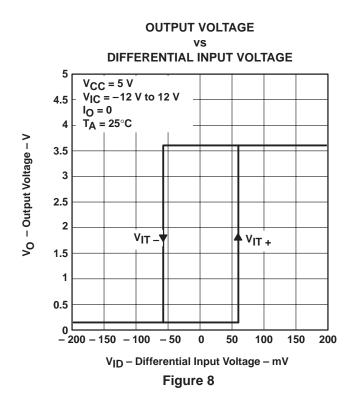
NOTES: A. C_L includes probe and jig capacitance.

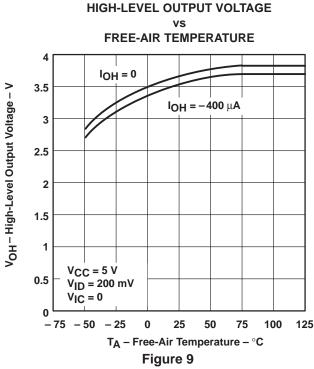
- B. All diodes are 1N3064 or equivalent.
- C. Enable G is tested with G high; G is tested with G low.

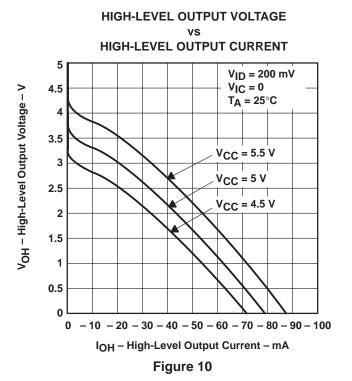
Figure 3. Load Circuit and Voltage Waveforms

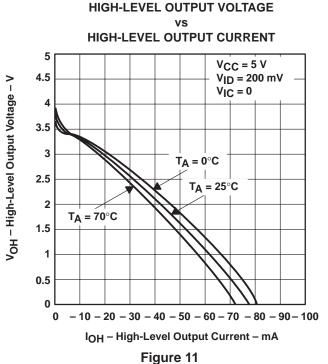












LOW-LEVEL OUTPUT VOLTAGE

FREE-AIR TEMPERATURE

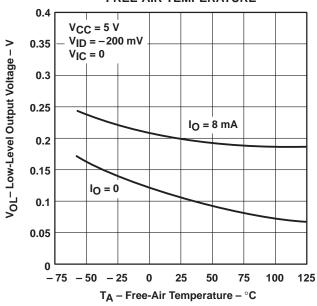


Figure 12

VOL - Low-Level Output Voltage - V

LOW-LEVEL OUTPUT VOLTAGE

VS

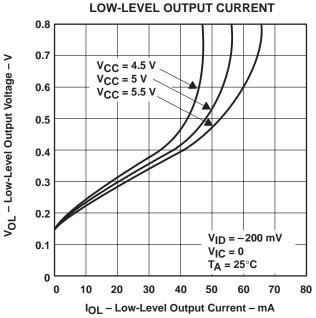


Figure 13

LOW-LEVEL OUTPUT VOLTAGE

VS

LOW-LEVEL OUTPUT CURRENT

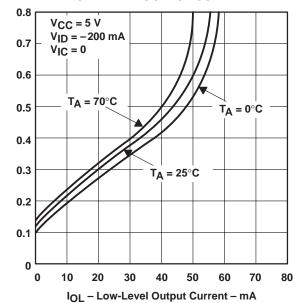
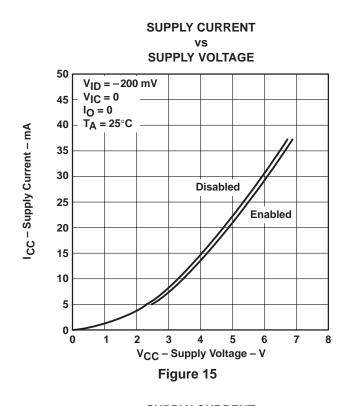
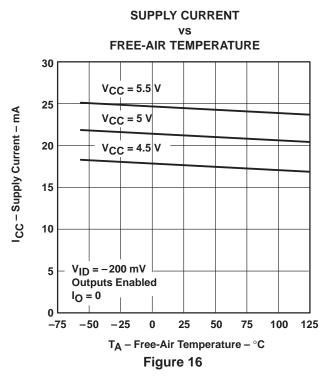
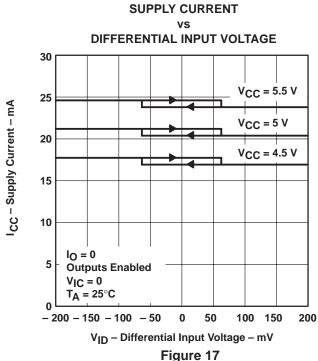
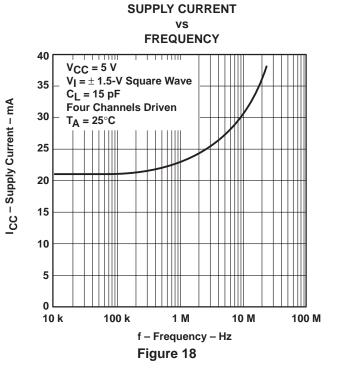


Figure 14







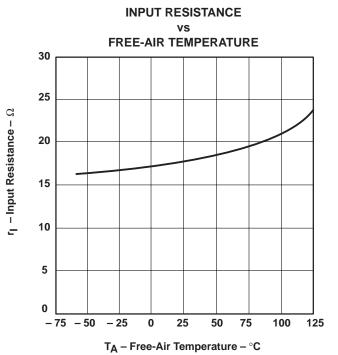


INPUT CURRENT

INPUT VOLTAGE TO GND

TYPICAL CHARACTERISTICS

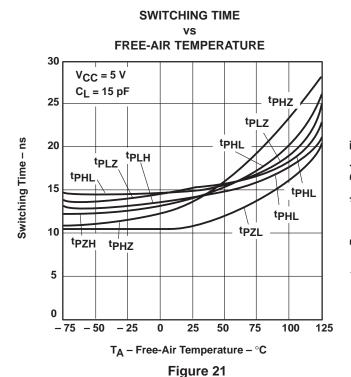
3

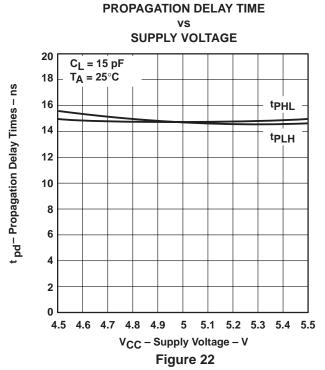


T_A = 25°C 2 I₁ - Input Current - mA 1 0 -1 - 2 - 3 -15 -10 0 5 10 15 -20 -5 20 V_I - Input Voltage to GND - V

Figure 19

Figure 20





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